

<b>U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</b>										<b>ATTY. DOCKET NO.</b> 37,437		<b>SERIAL NO.</b> 10/717,130	
<b>LIST OF DOCUMENTS CITED BY APPLICANT</b> (Use several sheets if necessary)										<b>APPLICANTS</b> Christos Paparizos, Stephen C. Jevne, Michael J. Seely			
<b>FILING DATE</b> November 18, 2003										<b>GROUP</b> UNKNOWN <b>1626</b>			

  

U.S. PATENT DOCUMENTS													
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE							
KS	AA	4 2 2 8 0 9 8	10/14/80	Aoki et al.	260	465.3							
	AB	4 4 1 4 1 3 3	11/08/83	Otake et al.	502	179							
	AC	4 6 5 9 6 8 9	04/21/87	Suresh et al.	502	311							
	AD	4 7 4 6 7 5 3	05/24/88	Brazdil, Jr. et al.	558	324							
	AE	4 9 3 9 2 8 6	07/03/90	Brazdil et al.	558	324							
	AF	5 0 9 3 2 9 9	03/03/92	Suresh et al.	502	212							
	AG	5 1 3 4 1 0 5	07/28/92	Paparizos et al.	502	205							
	AH	5 1 7 5 3 3 4	12/29/92	Suresh et al.	558	324							
	AI	5 2 1 2 1 3 7	05/18/93	Suresh et al.	502	212							
	AJ	5 2 3 5 0 8 8	08/10/93	Paparizos et al.	558	324							
KJ	AK	5 3 6 4 8 2 5	11/15/94	Neumann et al.	502	311							

  

FOREIGN PATENT DOCUMENTS													
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION								
					YES	NO							
KG	AL	JP 07 04 72 72 A 2	02/21/95	Japan									
	AM	C N 11 14 91 5 A	01/17/96	China									
	AN	JP 02 00 45 69 6 A	02/12/02	Japan									
	AO	C N 13 02 69 0 A	07/11/01	China									
	AP	C N 13 10 04 6 A	02/24/00	China									

  

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)		
	AR	
	AS	
	AT	

  

<b>EXAMINER</b> <u>Kamal Saeed</u>	<b>DATE CONSIDERED</b> <u>03/05/06</u>
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\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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										<b>FILING DATE</b> November 18, 2003		<b>GROUP</b> <del>UNKNOWN</del> 626		
<b>U.S. PATENT DOCUMENTS</b>														
*EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
KS	AU	5	5	8	3	0	8	4	12/10/96	Martin et al.	502	211		
	AV	5	5	8	3	0	8	6	12/10/96	Tenten et al.	502	249		
	AW	5	6	5	8	8	4	2	08/19/97	Midorikawa et al.	502	314		
	AX	5	6	6	3	1	1	3	10/02/97	Midorikawa et al.	502	314		
	AY	5	7	8	0	6	6	4	07/14/98	Kunitoshi Aoki	558	323		
	AZ	5	8	0	8	1	4	3	09/15/98	Karrer et al.	562	407		
	BA	5	8	4	0	6	4	8	11/24/98	Suresh et al.	502	306		
	BB	6	1	4	3	6	9	0	11/07/00	Komada et al.	502	211		
KS	BC	5	8	3	4	3	9	4	11/10/98	Chen et al.	502	302		
	BD	6	4	5	8	7	4	2	10/01/02	Paparizos et al.	502	301		
	BE													
<b>FOREIGN PATENT DOCUMENTS</b>														
		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
KS	BF	C	N	13	10	17	2	A	08/29/01	China	—	—	X	
	BG	C	N	12	30	45	9	A	10/06/99	China	—	—	X	
	BH	W	O	01	14	05	7	A	03/01/01	China	—	—	X	
	BI	C	N	12	87	88	2	A	03/21/01	China	—	—	X	
	BJ													
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>														
	BK													
	BL													
	BM													
EXAMINER		K. al. Sneed							DATE CONSIDERED		03/05/06			
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										<b>GROUP</b>						
<b>U.S. PATENT DOCUMENTS</b>																
*EXAMINER INITIAL		DOCUMENT NUMBER								DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
		AA	5	8	3	4	3	9	4							
KS	AA	5	8	3	4	3	9	4	07/16/02	Chen et al.	502	302				
	AB															
	AC															
	AD															
	AE															
	AF															
	AG															
	AH															
	AI															
	AJ															
	AK															
<b>FOREIGN PATENT DOCUMENTS</b>																
		DOCUMENT NUMBER								DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
		AL	E	P	12	23	16	3	A1					YES	NO	
KS	AL	E	P	12	23	16	3	A1	07/17/02	PCT Application						X
	AM	W	O	03	03	31	39	A1	09/25/02	PCT Application (Japan)						X
KS	AN	E	P	13	86	66	1	A1	02/04/04	PCT Application						X
	AO	W	O	02	08	33	02	A1	10/24/02	PCT Application (Japan)				X		
KS	AP															
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>																
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